PART ONE: General description			
Resist Process name Yael Hanein Author	Process Code Hanein@ee.washington.edu Contact Information (Email)	07/12/00 Last Update	
Etching of resist/organic material – leftovers Can modify process "resist" already saved on the RIE system. General description of process			

PART TWO: Details

Pressure Set	100	Oxygen Set	100
RF Power Set	150	CHF3 Set	0
End Point Set	900	SF6 Set	0
Process Time	15		
Base Pressure Set	150		

PART THREE: General Comments

Use before evaporation/deposition, or etching.

The Oxygen-plasma etches some of the resist so make sure to limit the length of the process. Approx. etch rate -0.4mic/min.